

**Comprehensive performance and robustness analysis of 2D turn models for network-on-chips**  
**Azad, Siavoosh Payandeh; Niazimand, Behrad; Janson, Karl; Kogge, Thilo; Raik, Jaan; Jervan, Gert; Hollstein, Thomas**  
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**NoCDepend : a flexible and scalable dependability technique for 3D networks-on-chip**  
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